The Ram an Fingerprint of G raphene

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G raphene is the two-dimensional (2d) building block for carbon allotropes of every other dimensionality. It can be stacked into 3d graphite, rolled into 1d nanotubes, or wrapped into 0d fullerenes. Its recent discovery in free state has nally provided the possibility to study experimentally its electronic and phonon properties. Here we show that graphene's electronic structure is uniquely captured in its R am an spectrum that clearly evolves with increasing number of layers. R am an ngerprints for single-, bi- and few-layer graphene re ect changes in the electronic structure and electron-phonon interactions and allow unambiguous, high-throughput, non-destructive identic cation of graphene layers, which is critically lacking in this emerging research area.

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The current interest in graphene can be attributed to three main reasons. First, its electron transport is described by the D irac equation and this allows access to the rich and subtle physics of quantum electrodynamics in a relatively simple condensed matter experiment [1, 2, 3, 4, 5]. Second, the scalability of graphene devices to nano-dimensions [6, 7, 8, 10, 11] makes it a promising candidate for electronic applications, because of its ballistic transport at room tem perature combined with chem ical and mechanical stability. R em arkable properties extend to bi-layer and few -layers graphene [4, 5, 6, 8, 12]. Third, various form sofgraphite, nanotubes, buckyballs and others can all be viewed as derivatives of graphene and, not surprisingly, this basic material has been intensively investigated theoretically for the past fly years [13]. The recent availability of graphene [1] at last allows to probe it experimentally, which paves the way to better understanding the other allotropes and to resolve controversies.

G raphene sam ples can be obtained using the procedure of R ef. [1], i.e. m icro-m echanical cleavage of graphite. A lternative procedures, such as exfoliation and grow th, so far only produced multi-layer sam ples [6, 8, 9], but it is hoped that in the near future e cient grow th m ethods will be developed, as happened for nanotubes. D espite the wide use of the m icro-m echanical cleavage, the identi cation and counting of graphene layers is a m a jor hurdle. M onolayers are a great m inority am ongst accom panying thicker akes. They cannot be seen in an optical m icroscope on m ost substrates. G raphene layers only becom e visible when deposited on the top of oxidized Si substrates with a nely tuned thickness of the oxide layer (typically, 300 nm of SiO₂) because, in this case, even a m onolayer adds to the optical path of re-

ected light to change the interference color with respect to the empty substrate [1, 4]. A tom ic Force M icroscopy (AFM) has been so far the only method to identify sin-

gle and few layers, but it is low throughput. Moreover, due to the chem ical contrast between graphene and the substrate (which results in an apparent chem ical thickness of 0.5-1nm, much bigger of what expected from the interlayer graphite spacing [1, 4]), in practice, it is only possible to distinguish between one and two layers by AFM if Im s contain folds or wrinkles [1, 4]. This poses a m a pr limitation to the range of substrates and is a setback for the widespread utilization of thism aterial. Here, we show that graphene's electronic structure is uniquely captured in its R am an spectrum. R am an ngerprints for single-, bi- and few -layers re ect changes in the electronic structure and allow unam biguous, high-throughput, nondestructive identi cation of graphene layers, which is critically lacking in this emerging research area.

The sam ples studied in this work were prepared by m icrom echanical cleavage [1]. To provide the most de nitive identication of single and bi-layer graphene (beyond the layer counting procedures by AFM) we perform Transm ission Electron M icroscopy (TEM) on som e of the samples to be measured by Raman spectroscopy. Sam ples for TEM are prepared following a similar process to that previously utilized to m ake free-standing and TEM com patible carbon nanotube devices [14]. In addition, this allow sus to have free-standing layers on a grid easily seen in the optical R am an m icroscope, facilitating their location during Ram an measurements, Fig. 1 (a). Electron di raction is done in a Zeiss 912 microscope at a voltage of 60kV, and high-resolution in ages are obtained with a Philips CM 200 m icroscope at 120kV.A HR-TEM analysis of foldings at the edges or within the free hanging sheets gives the num ber of layers by direct visualization, since at a folding the sheet is locally parallel to the beam, Fig. 1 (b-e). Edges and foldings of the one or two layers are dom inated by one or two dark lines. The num ber of layers is also obtained by a di raction analysis of the freely suspended sheets for varying incidence angles,

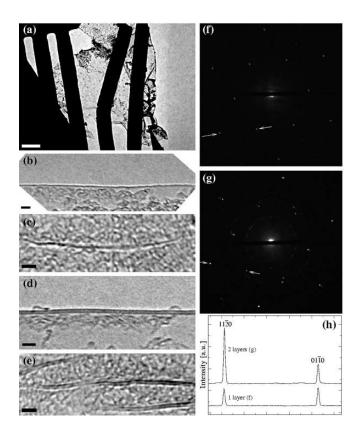


FIG.1: (a) TEM image of a suspended graphene sheet. The metal grid is also visible in the optical microscope. (b) High resolution image of a folded edge of single layer graphene and (c) a wrinkle within the single layer sheet. (d) Folded edge of a two-layer sample and (e) internal foldings of the two-layer sheet. The amorphous contrast on the sheets is most likely due to hydrocarbon adsorbates on the sam ples that were cracked by the electron beam . (f) E lectron di raction pattern for close to norm al incidence from single layer graphene and (g) from two layers. (h) Intensity pro le plot along the line indicated by the arrows in (f+g). The relative intensities of the spots in the two-layer sheet are consistent only with A-B (and not A-A) stacking. Scale bars: (a) 500 nm; (b-e) 2 nm.

and con m s the number of layers seen in the foldings, Fig.1(d,e). In particular, the di raction analysis of the bi-layer shows that it is A-B stacked (the intensity of the 11-20 di raction spots (outer hexagon) is roughly twice that of the 1-100 (inner hexagon), Fig.1(h), in agreem ent with in age simulations. This con m s that multi-layer graphene m aintains the sam e stacking as graphite.

U npolarized R am an spectra are measured on single, bi and multi-layers on Si+SiO₂. Some are then processed into free-hanging sheets, also measured by TEM as described above, and measured again by R am an spectroscopy after TEM. The measurements are performed at room temperature with a Renishaw spectrometer at 514 and 633 nm. A 100 objective is used. Extreme care is taken to avoid sample dam age or laser induced heating. Measurements are performed from 4mW to 0.04mWincident power. No signi cant change in the spectra is observed in this power range both for free standing and supported samples. The Raman spectra of suspended and on-substrate graphene are similar, one of the main di erences being a D peak observed for the much smaller samples used for TEM. We also measure the reference bulk graphite used to produce the layers.

Fig. 2(a) compares the 514 nm Raman spectra of graphene and bulk graphite. The two most intense fea-1580 cm^{-1} and a band at tures are the G peak at 2700cm¹, historically named G', since it is the second most prominent band always observed in graphite sam ples[15]. The G peak is due to the doubly degenerate zone centre E_{2q} m ode [16]. On the contrary, the G' band has nothing to do with the G peak, but is the second order of zone boundary phonons. Since zone-boundary phonons do not satisfy the R am an fundam ental selection rule, they are not seen in the st order R am an spectra of defect-free graphite [17]. Such phonons give rise to a Ram an peak at 1350 cm⁻¹ in defected graphite, called D peak [16]. Thus, for clarity, we refer to the G' peak as 2D.Fig.2(a) shows that no D peak is observed in the centre of the graphene layers. This proves the absence of a signi cant number of defects in the structure. As expected, a D peak is only observed at the sam ple edge, Fig. 2(d). Fig. 2(a) shows a signi cant change in the shape and intensity of the 2D peak of graphene com pared to bulk graphite. The 2D peak in bulk graphite consists of two components $2D_1$ and $2D_2$ [15, 17], roughly 1=4 and 1=2 the height of the G peak, respectively. Here we measure a single, sharp 2D peak in graphene, roughly 4 tim esm ore intense than the G peak. Notably, the G peak intensity of single layer and bulk graphite is comparable (note that Fig. 2 (a) is re-scaled to show a sim ilar 2D intensity) and the G position is 3-5 cm 1 higher than bulk graphite. The change in shape of the 2D band is nicely con med in Fig. 2(d), which compares the D peak observed on the graphite edge with that of the graphene edge. The graphene D peak is a single sharp peak, while that of graphite is a band consisting of two peaks D₁ and D₂[15]. Fig. 2 (b,c) plot the evolution of the 2D band as a function of the number of layers for 514.5 nm and 633 nm excitations. These immediately indicate that bilayer graphene has a much broader and up-shifted 2D band with respect to graphene. This band is also quite di erent from bulk graphite. It has 4 com ponents, $2D_{1B}$, $2D_{1A}$, $2D_{2A}$, $2D_{2B}$, 2 of which, $2D_{1A}$ and $2D_{2A}$, have higher relative intensities than the other 2, as indicated in Fig. 2(e). Fig. 2(b,c) show that a further increase of the number of layers leads to a signi cant decrease of the relative intensity of the lower frequency 2D₁ peaks. For m ore than 5 layers the R am an spectrum becom es hardly distinguishable from that of bulk graphite. Thus R am an spectroscopy can clearly identify a single layer, from bilayer from few (less than 5) layers. This also explains why previous experim ents on nano-graphites, but not individual or bi-layer graphene, failed to identify these features

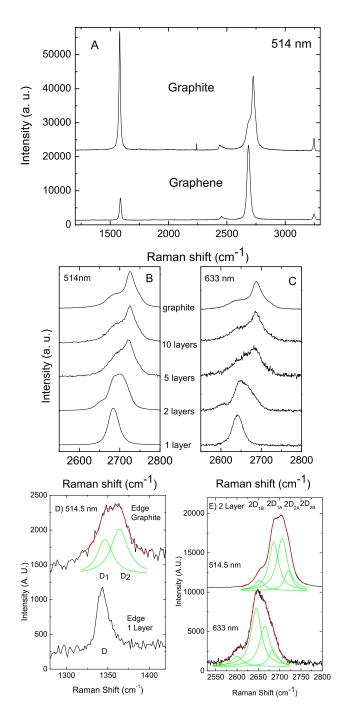


FIG.2: (a) C om parison of R am an spectra at 514 nm for bulk graphite and graphene. They are scaled to have similar height of the 2D peaks. (b) Evolution of the spectra at 514 nm with the num ber of layers. (c) Evolution of the R am an spectra at 633 nm with the num ber of layers. (d) C om parison of the D band at 514 nm at the edge of bulk graphite and single layer graphene. The Fit of the D_1 and D_2 components of the D band of bulk graphite is shown. (e) The four components of the 2D band in 2 layer graphene at 514 nm and 633 nm.

[18, 19]. In particular, it was noted from early studies that turbostratic graphite (i.e. without AB stacking) has a single 2D peak [20]. However, its Full W idth at Half Maximum (FW HM) is 50 cm 1 almost double that of the 2D peak of graphene and upshifted of 20 cm 1 . Turbostratic graphite also often has a rst order D peak [20]. SW NTs show a sharp 2D peak sim ilar to that we measure here for graphene [21]. The close sim ilarity (in position and FW HM) of our m easured graphene 2D peak and the 2D peak in SW NTs of 1-2 nm diam eter [22] in plies that curvature e ects are sm all for the 2D peak for SW NTs in this diam eter range, the most commonly found in experim ents. This questions the assumption that the 2D peak in SW NT should scale to the up-shifted average 2D peak position in bulk graphite for large diam eters [22]. This assumption was utilized to ta scaling law relating SW NT diam eter and 2D peak position, which is often used to derive the diam eter of inner tubes in double wallnanotubes [22, 23]. Despite the sim ilarities, it is in portant to note that there are major di erences between graphene and SW NT R am an spectra, which allow to eas-

curvature split the two degenerate modes of the G peak in SW NTs [21], resulting in G^+ and G^- peaks. We now explain why graphene has a single 2D peak, and why this splits in four components in bi-layer graphene. Several authors previously attempted to explain the double structure of the 2D peak in graphite [15, 17, 18, 19, 20, 24], how ever they alw aysneglected the evolution of the electronic bands with the number of layers, which is, on the contrary, the key fact. The 2D peak in graphene is due to two phonons with opposite momentum in the highest optical branch near the K (A_1^0) symmetry at K) [16, 25, 26]. Fig. 2 shows that this peak changes in position with varying excitation energy. This is due to a Double Resonance (DR) process, which links the phonon wave-vectors to the electronic band structure [27]. W ithin DR, Ram an scattering is a third order process involving four virtual transitions: i) a laser induced excitation of an electron/hole pair (a! b verti-

ily distinguish these materials. Indeed, con nem ent and

caltransition in Fig.3(a)); ii) electron-phonon scattering with an exchanged momentum q close to K (b! c); iii) electron-phonon scattering with an exchanged momentum q (c! b); iv) electron/hole recombination (b! a). The DR condition is reached when the energy is conserved in these transitions. The resulting 2D R am an frequency is twice the frequency of the scattering phonon, with q determ ined by the DR condition. For sim plicity, Fig. 3(a,b) neglect the phonon energy and do not show the equivalent processes for hole-phonon scattering.

C onsistent with the experim ental observation of a single component for the 2D peak in single layer graphene, Fig. 3(a,b) only shows the phonon satisfying DR conditions with momentum q > K, along the K M direction (K < q < M). The other two possible DR phonons, with q < K and q K, give a much smaller contribution

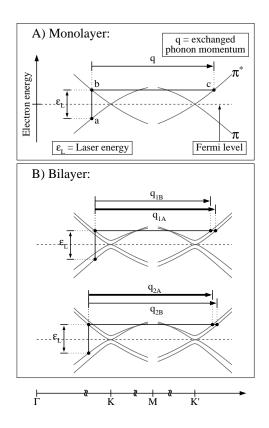


FIG. 3: DR scheme for the 2D peak in (a) single layer and (b) bi-layer graphene.

514.5	2 Layers				
Experim ental	-44	-10	+ 10	+ 25	
T heory	-44	-11	+ 11	+ 41	
633					
Experim ental	-55	-10	+ 10	+ 30	
T heory	-44	-9	+ 9	+ 41	

TABLE I: Relative splitting of 2D components in bi-layer graphene. In each case, we show the shift with respect to the average frequency of the two m ain peaks. The four columns of the bi-layer correspond to processes q_{1B} , q_{1A} , q_{2A} , q_{2B} , respectively. The theoretical values are obtained by multiplying the DR q vectors determ ined from the DFT electronic bands by dw/dq= 645 cm⁻¹ A. Here dw/dq is the ratio between the m easured shift of the 2D peak frequency with the laser energy in graphene (99 cm⁻¹/eV), and the corresponding variation of the DR q vector computed from the DFT electronic bands.

to the Ram an intensity. In fact, the q<K phonon involves a smaller portion of the phase-space because of the band-structure trigonal warping (see Fig.4 of Ref. [28] and related discussion) and the q K phonon has a zero electron-phonon coupling for this transition, as discussed in Ref [26] (see footnote 24, for q K, $^{00} = 0$) and Ref. [24]. This di ers from the models of Ref. [19, 24], which predict 2 sim ilar components for the D peak even in single layer, in disagreem ent with the experim ents of Fig.2. 4

We now examine the bi-layer case. The observed 4 components of the 2D peak could in principle be attributed to two di erent mechanisms: the splitting of the phonon branches [15, 17, 20, 29], or the spitting of the electronic bands [25]. To ascertain this we compute the phonon frequencies [26] for both single and bi-layer graphene (stacked AB, as indicated by TEM), at the q corresponding to the DR condition for the 514 and 633 nm lasers. The splitting of the phonon branches is < 1.5 cm 1 , much smaller than the experimentally observed 2D splitting. Thus, this is solely due to electronic bands e ects. In the bi-layer, the interaction of the graphene planes causes the and bands to divide in four bands, with a di erent splitting for electrons and holes, Fig. 3(b). Am ongst the 4 possible optical transitions, the incident light couples more strongly the two transitions shown in Fig. 3(b). The two almost degenerate phonons in the highest optical branch couple all electron bands amongst them . The resulting four processes involve phonons with m om enta q_{1B} , q_{1A} , q_{2A} , and q_{2B} , as shown in Fig. 3 (b). The four corresponding processes for the holes, and those associated to the 2 less intense optical transitions [not shown in Fig. 3(b)], are associated to m om enta alm ost identical to q_{1B} , q_{1A} , q_{2A} , q_{2B} . These wave-vectors correspond to phonons with di erent frequencies, due to the strong phonon dispersion around K induced by the electron-phonon coupling [26]. They produce four di erent peaks in the Ram an spectrum of bi-layer graphene. Tab. I reports the expected splittings and show s that they com pare very wellw ith experiments.

In conclusion, graphene's electronic structure is uniquely captured in its Ram an spectrum, that clearly evolves with the number of layers. Ram an ngeprints for single-, bi- and few-layer graphene re ect changes in the electronic structure and electron-phonon interactions and allow unambiguous, high-throughput, nondestructive identi cation of graphene layers.

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